Inventor: Mark Feldman Docket No.: MEIP122467



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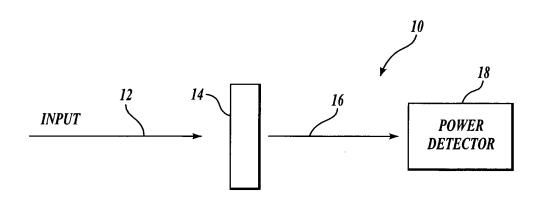


Fig.1A. (PRIOR ART)

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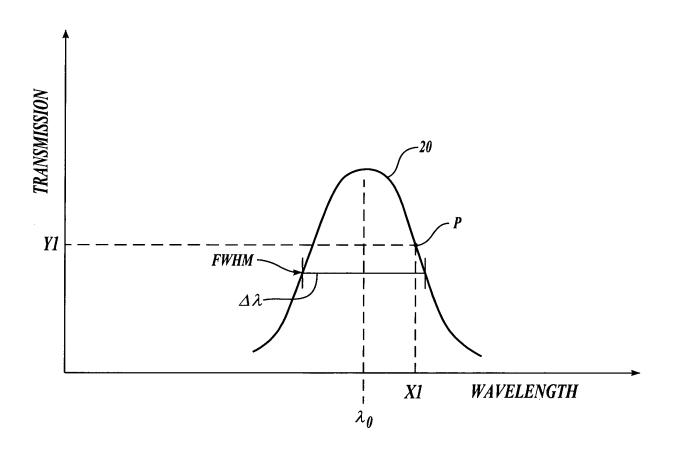


Fig. 1B. (PRIOR ART)

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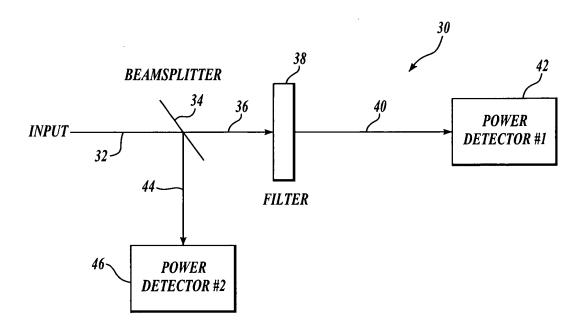
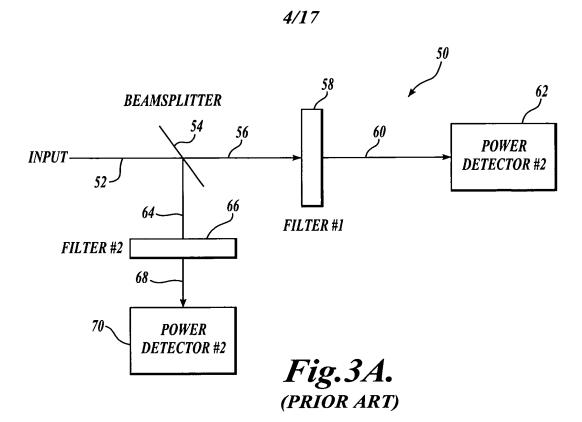


Fig. 2. (PRIOR ART)

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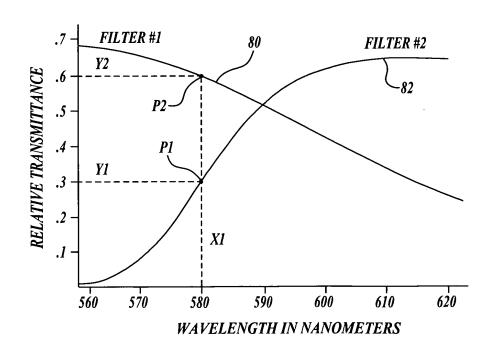


Fig. 3B. (PRIOR ART)

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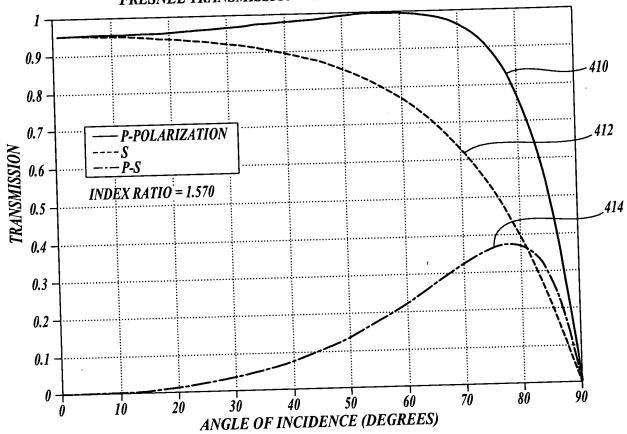


Fig.4.

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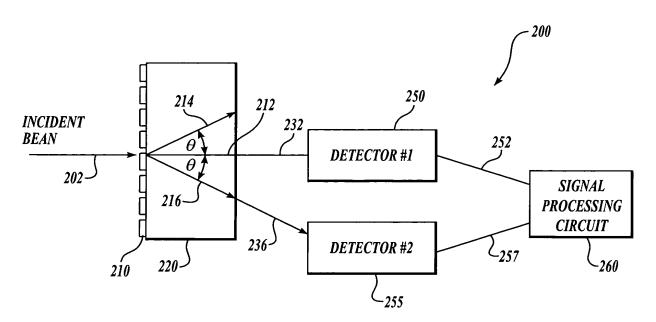
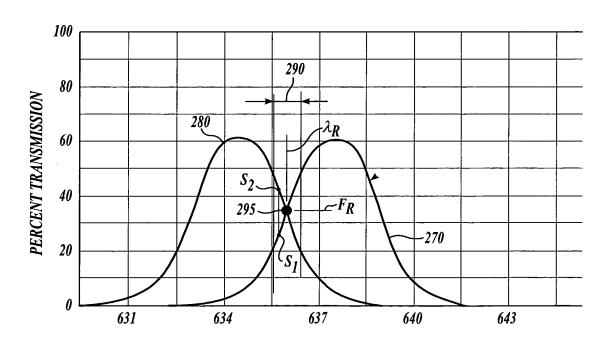


Fig.5A.



WAVELENGTH IN NANOMETERS

Fig.5B.

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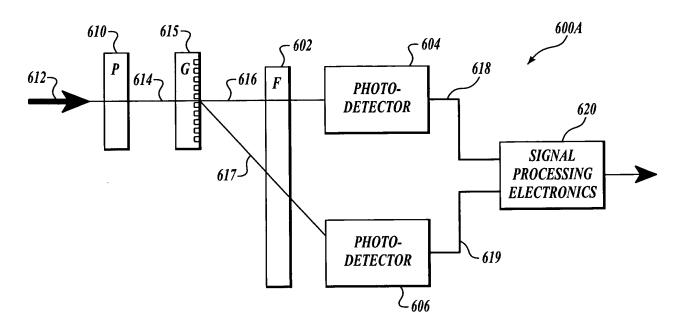


Fig. 6A.

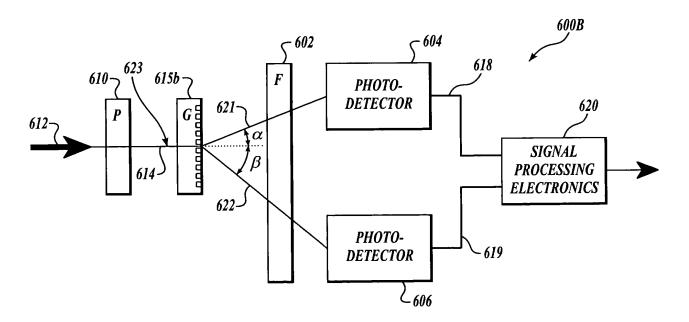


Fig. 6B.

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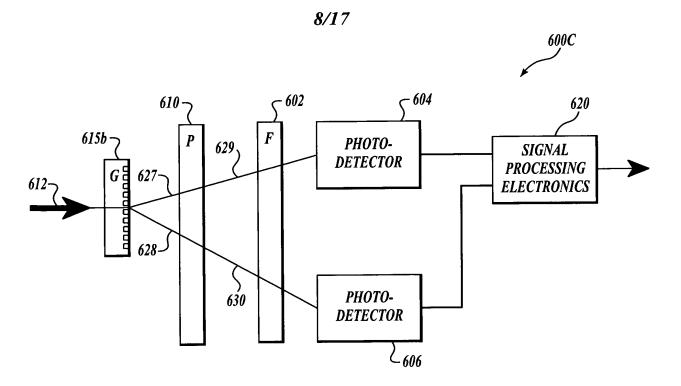


Fig.6C.

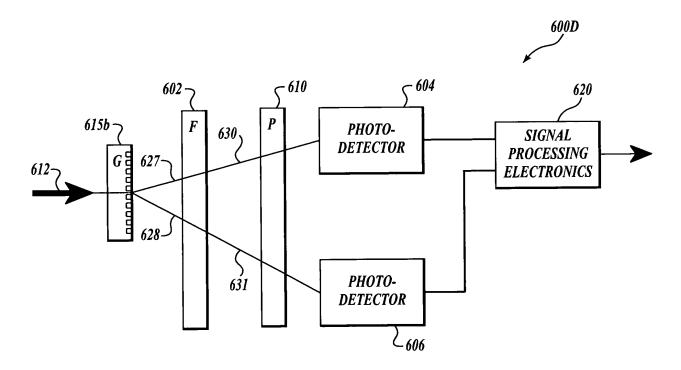


Fig.6D.

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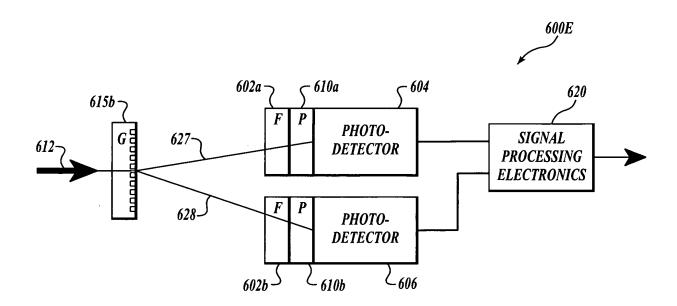


Fig. 6E.

Title: IMPROVED WAVELENGTH DETECTOR U.S. Patent Application 10/814,755 Filed: March 31, 2004 Inventor: Mark February 100 Docket No.: MEIP122467

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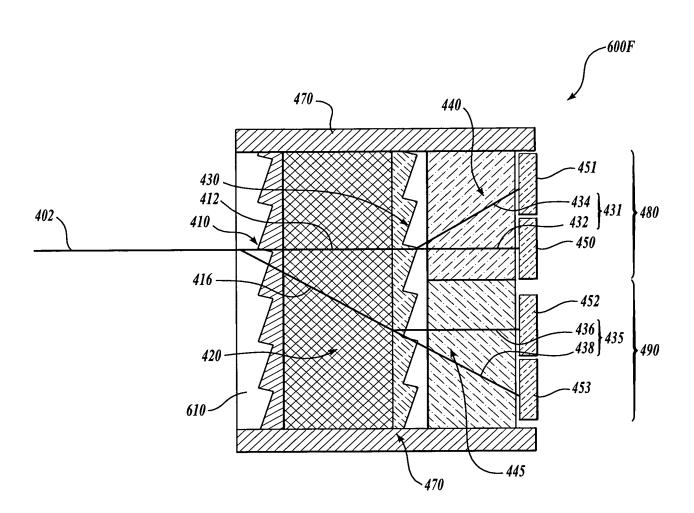


Fig.6F.

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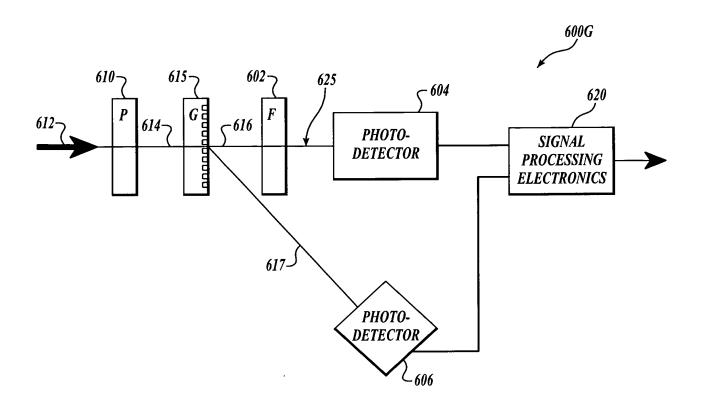


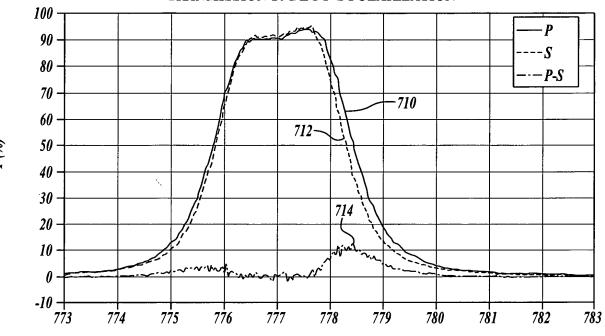
Fig.6G.

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WAVELENGTH IN NANOMETERS

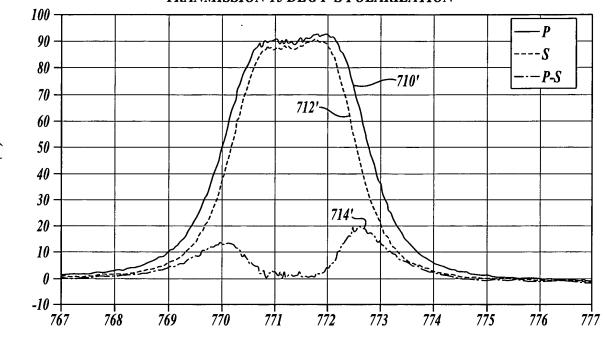
Fig.7A.

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WAVELENGTH IN NANOMETERS

Fig. 7B.

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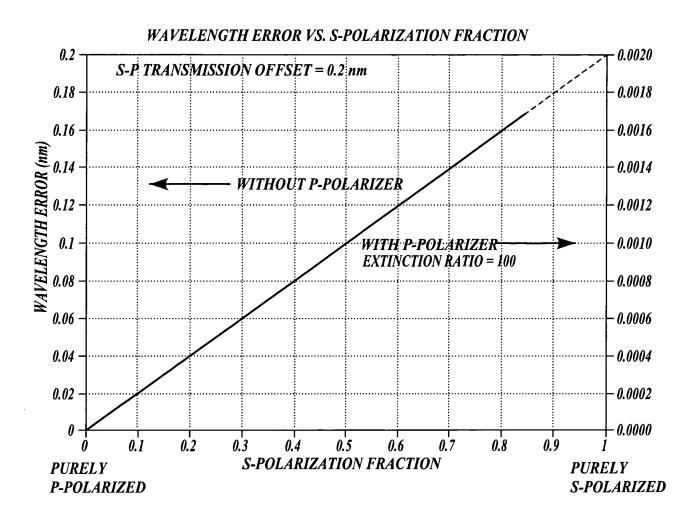


Fig. 8.

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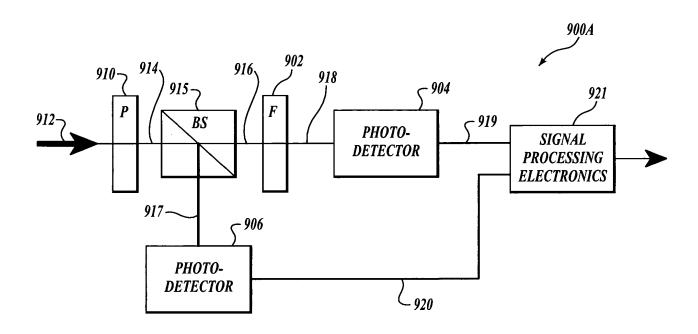


Fig.9A.

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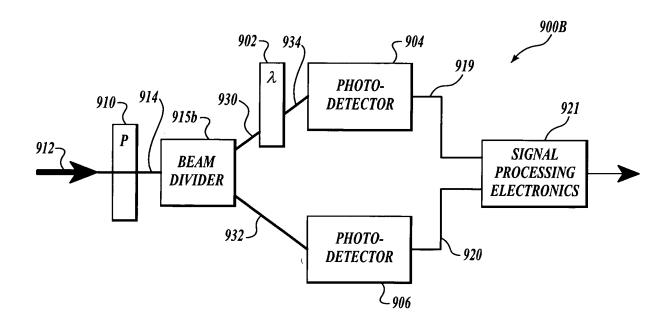


Fig.9B.

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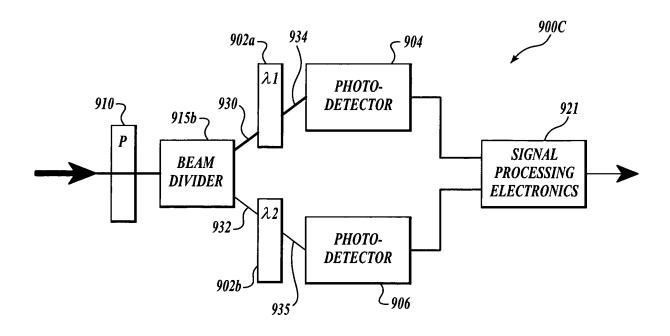


Fig.9C.